

KC Link Auto C0G, Ceramic, 0.033 uF, 10%, 500 VDC, C0G, SMD, MLCC, Ultra-Stable, Low Loss, High Voltage, Automotive Grade, 2220



| Dimensions | |
|------------|-----------------|
| Chip Size | 2220 |
| L | 5.9mm +/-0.4mm |
| W | 5mm +/-0.4mm |
| T | 2.5mm +/-0.20mm |
| B | 0.6mm +/-0.35mm |

| Packaging Specifications | |
|--------------------------|--------------------------|
| Packaging: | T&R, 180mm, Plastic Tape |
| Packaging Quantity: | 500 |

| General Information | |
|---------------------|---|
| Series: | KC Link Auto C0G |
| Style: | SMD Chip |
| Description: | SMD, MLCC, Ultra-Stable, Low Loss, High Voltage, Automotive Grade |
| Features: | Ultra-Stable, Low Loss, Automotive Grade |
| RoHS: | Yes |
| Termination: | Tin |
| Marking: | No |
| Qualifications: | AEC-Q200 |
| AEC-Q200: | Yes |
| Component Weight: | 320 mg |
| Shelf Life: | 78 Weeks |
| MSL: | 1 |

| Specifications | |
|---|------------------------|
| Capacitance: | 0.033 uF |
| Measurement Condition: | 1 kHz 1.0Vrms |
| Capacitance Tolerance: | 10% |
| Voltage DC: | 500 VDC |
| Dielectric Withstanding Voltage: | 750 VDC |
| Temperature Range: | -55/+150°C |
| Temperature Coefficient: | C0G |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC): | 30 ppm/C, 1kHz 1.0Vrms |
| Dissipation Factor: | 0.1% 1 kHz 1.0Vrms |
| Aging Rate: | 0% Loss/Decade Hour |
| Insulation Resistance: | 30.303 GOhms |

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